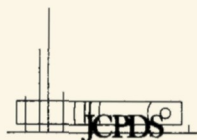


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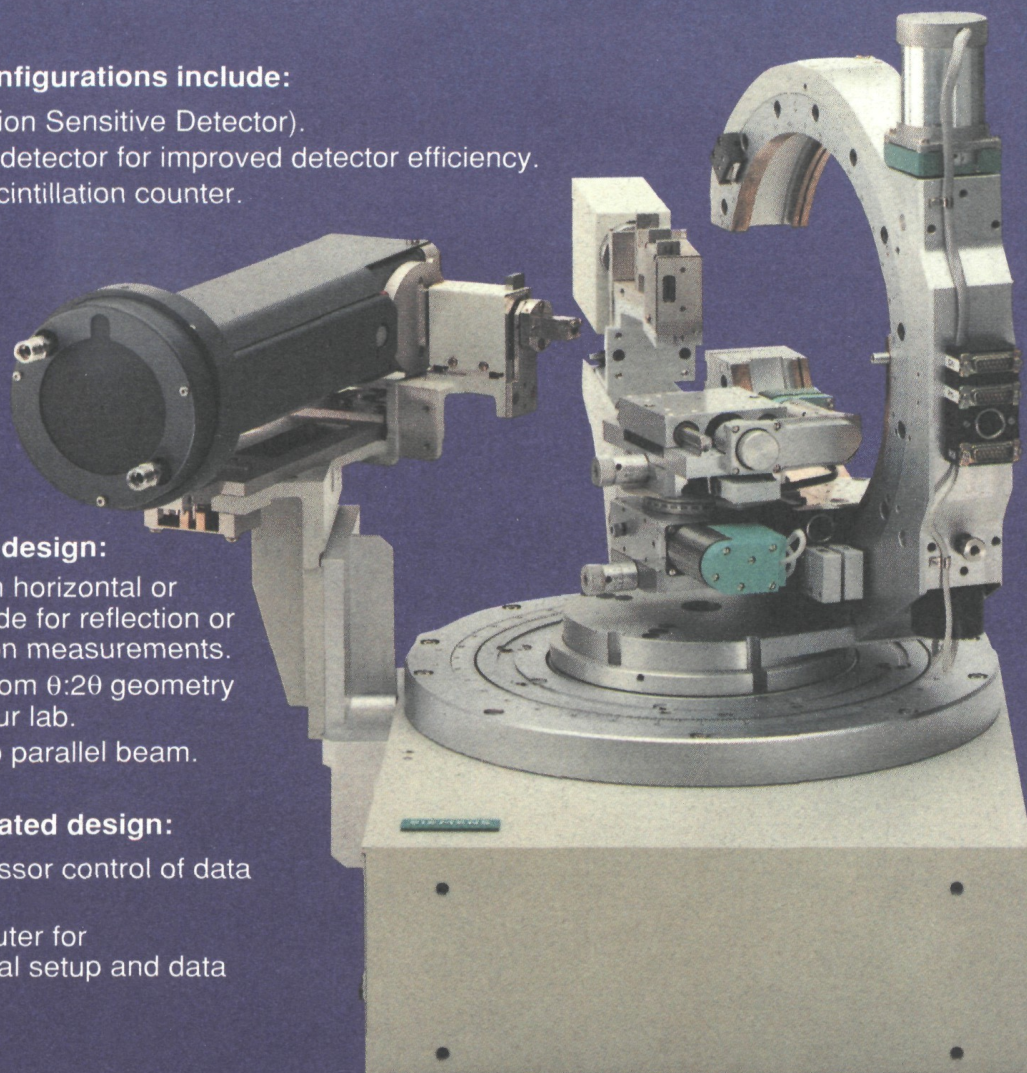
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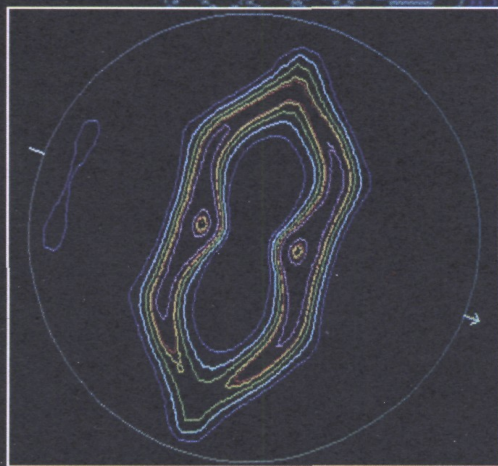
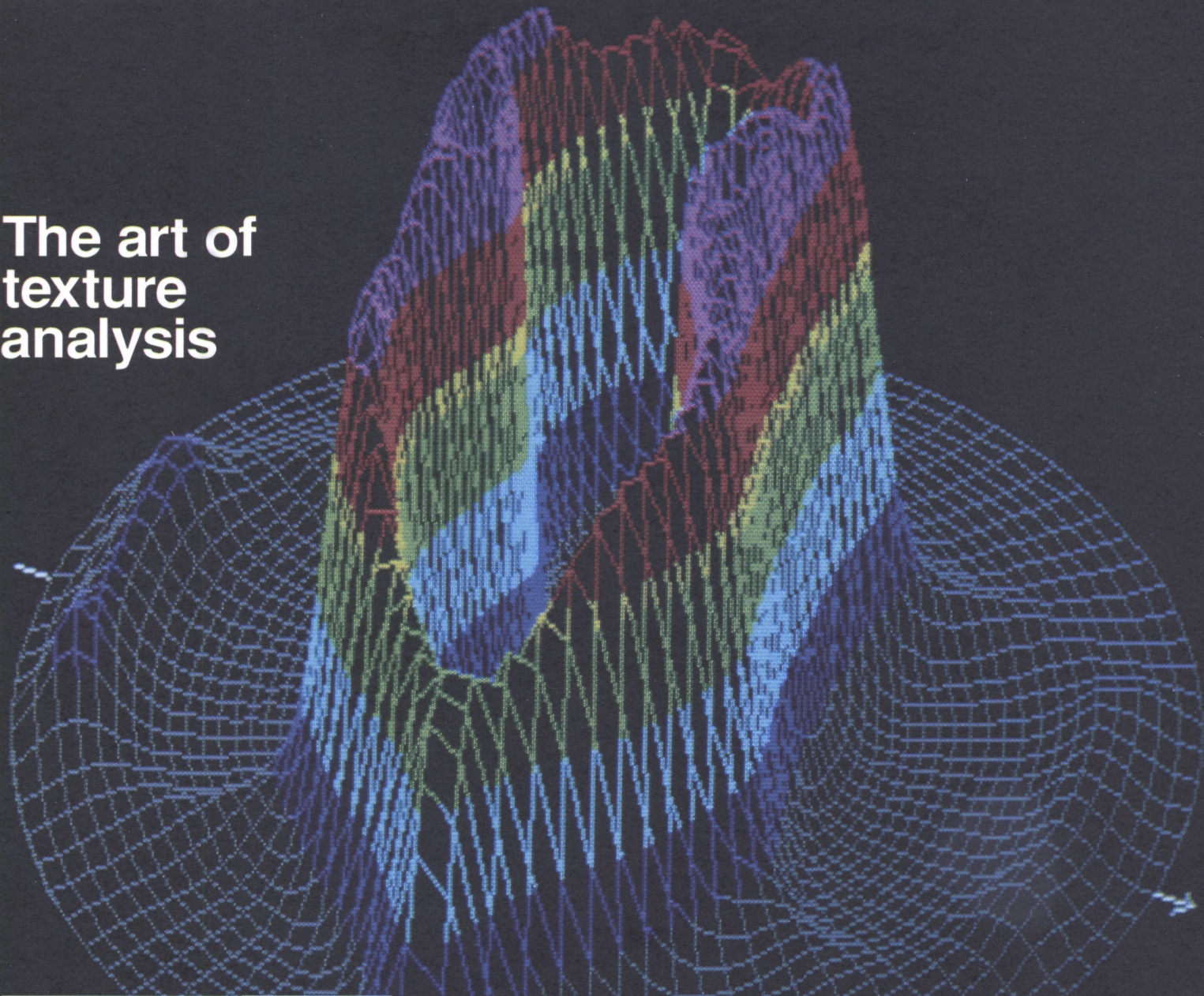
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Now it's the ICDD Clinic

After thirty years Henry Chessin's SUNYA X-ray Clinic is changing sponsors. With Dr. Chessin's retirement, the International Centre for Diffraction Data has undertaken responsibility for the X-ray diffraction summer sessions which he so long and capably directed.

The First ICDD Clinic will be at Penn State University

The ICDD will offer two one-week summer sessions to be held on the University Park Campus at State College, Pennsylvania.

First week (basics): June 18-27.
Second week (advanced): June 22-29.

The faculty will include: Ron Jenkins, Principal Scientist, at the International Centre, and Professors Earle Ryba, Deane Smith and Gerald Johnson, Jr. of Penn State. Henry Chessin is a consultant for the 1990 program.

You can register now

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PD-3

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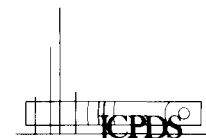
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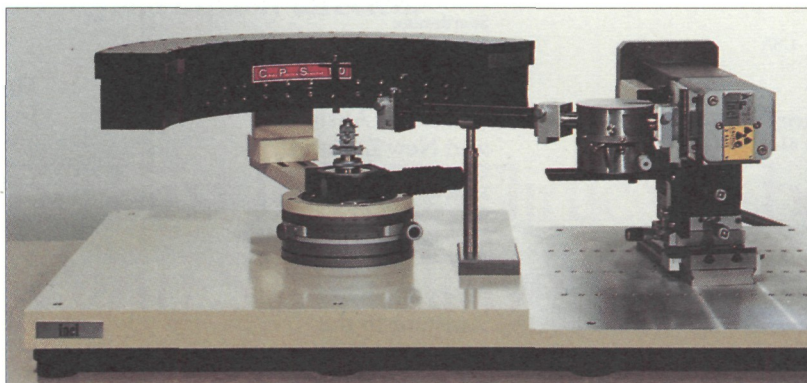
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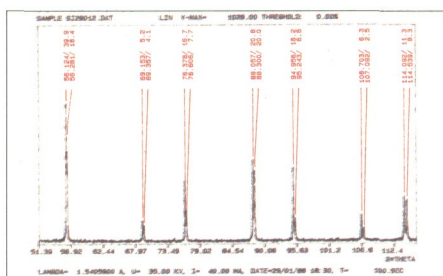
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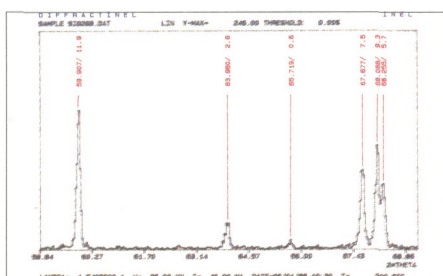
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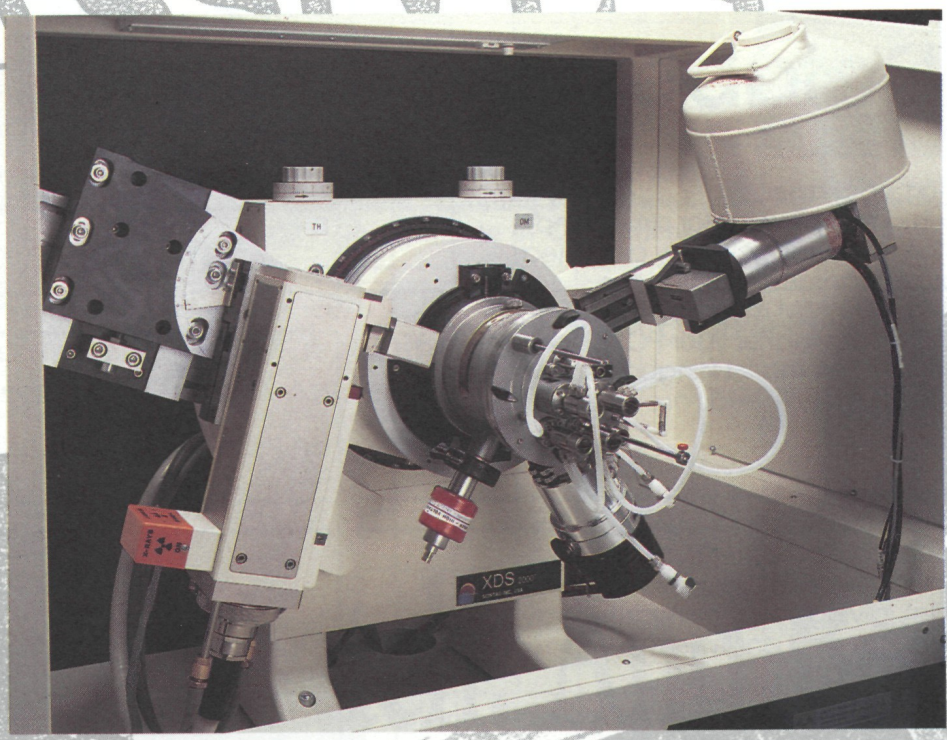
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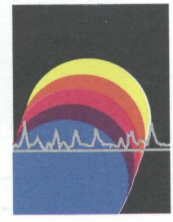
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Chronicle Staff Writers

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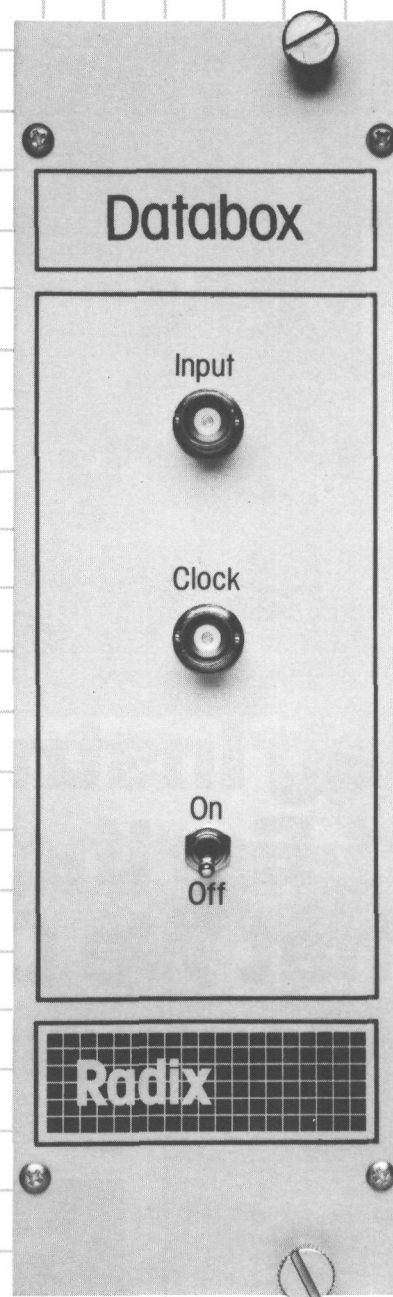
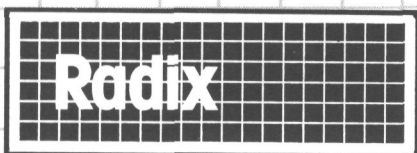
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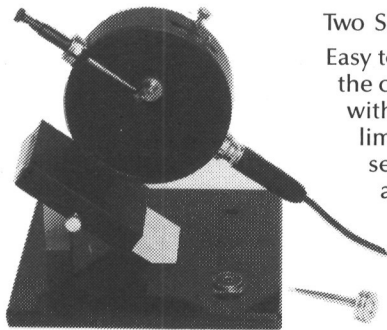
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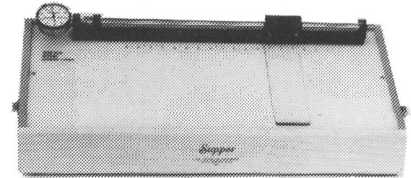
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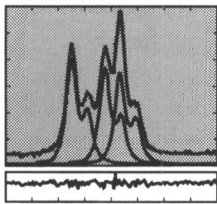
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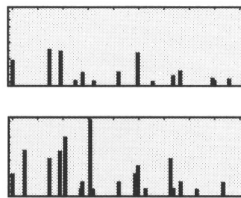
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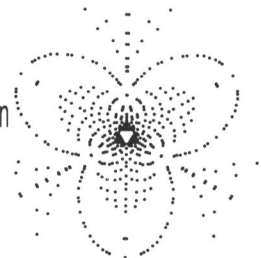
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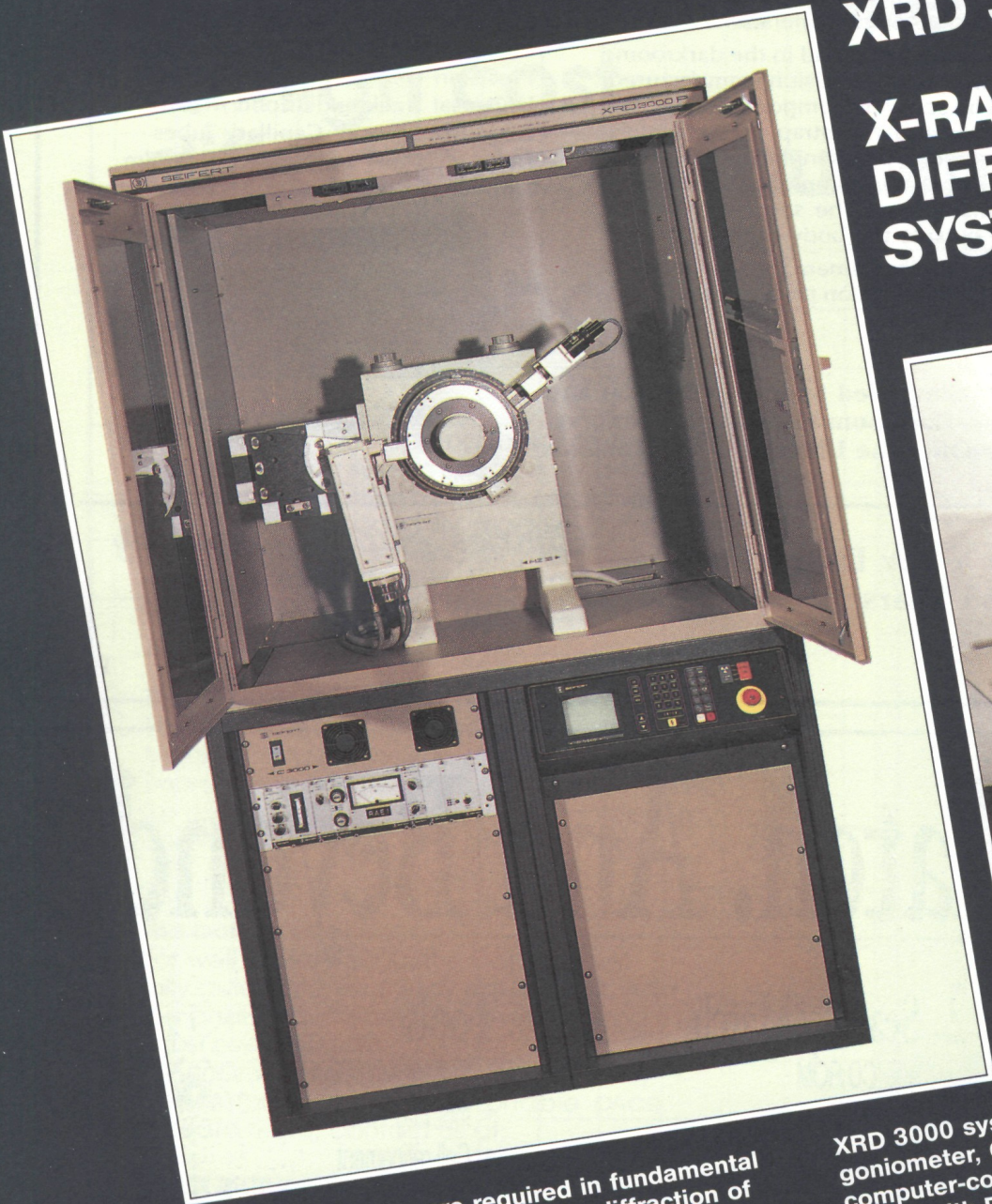
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PD9



Second Announcement...

The first international congress on X-ray Analytical Methods for Materials Analysis will be held in Honolulu, August 12-16, 1991, at the Hilton Hawaiian Village.

Congress Theme...

The major thrust of this meeting will be related to the practical aspects involved in X-ray methods for materials analysis. This will be in keeping with the tradition of the Australian X-Ray Analytical Association (AXAA), the Denver X-Ray Conference and the X-Ray Chemical Analysis Group of the Japan Society of Analytical Chemistry.

To be discussed will be the use of X-ray methods based on Powder Diffraction, Fluorescence, Surface Analysis, Absorptiometry, Column Electron Diffraction and Thin Film Characterization by X-ray Diffraction, and Trace Analysis and Thin Film Characterization by X-Ray Fluorescence.

A two day pre-congress workshop program will be held at the University of Hawaii at Hilo, on August 8 and 9.

PICXAM is organized by:

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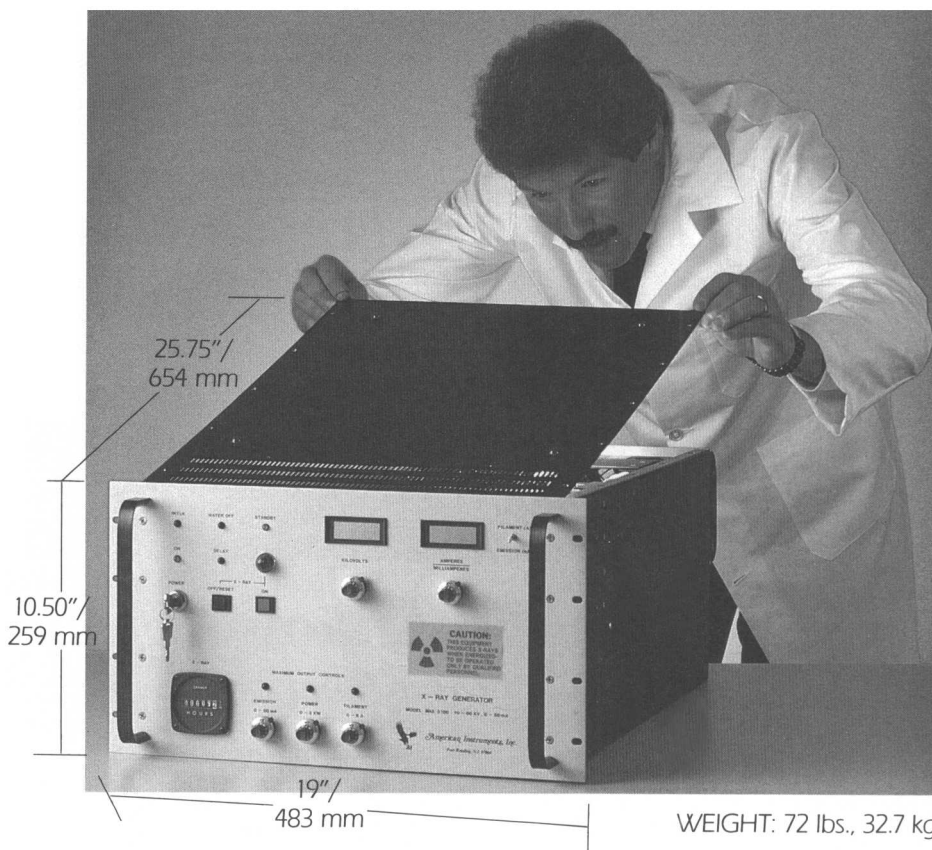
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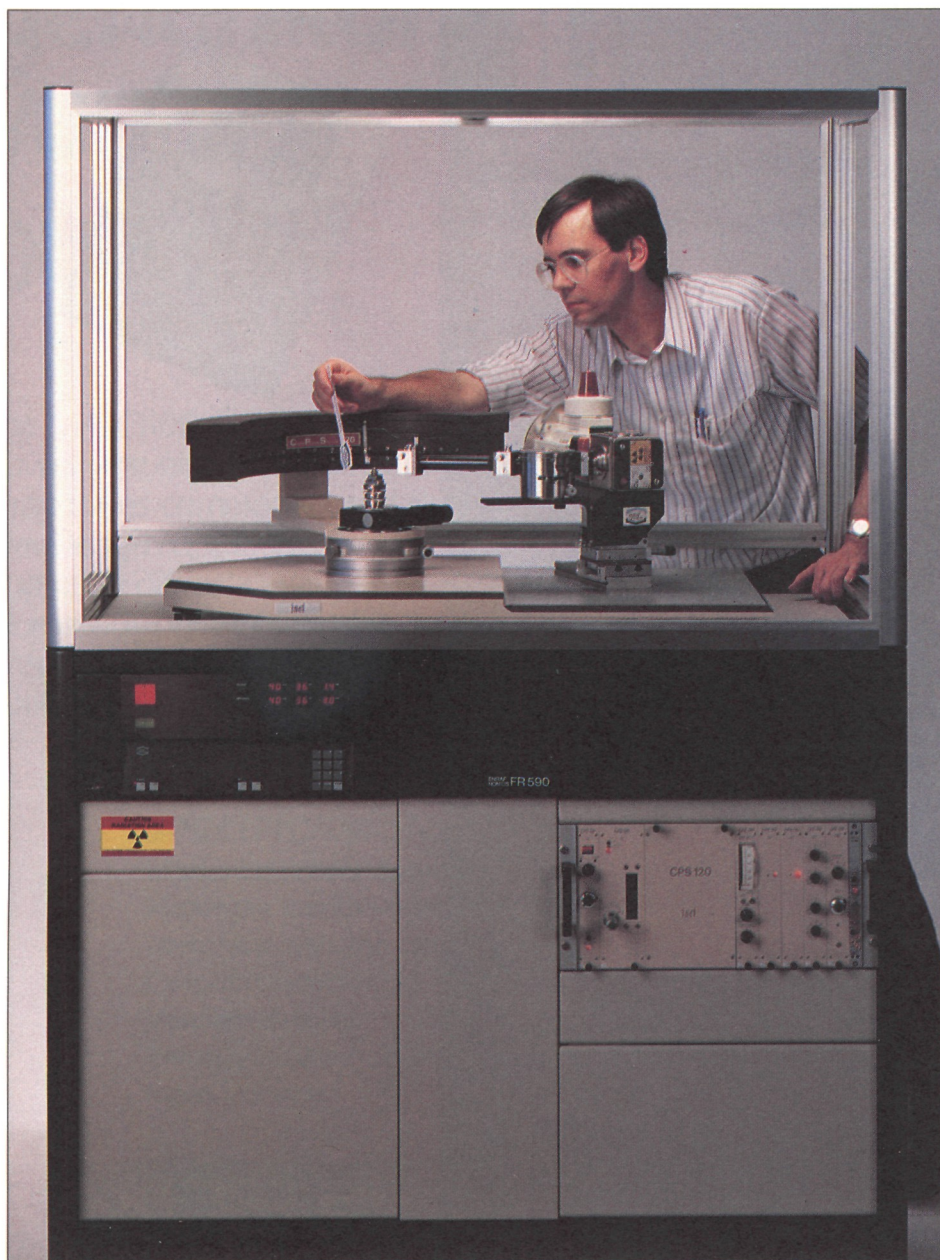
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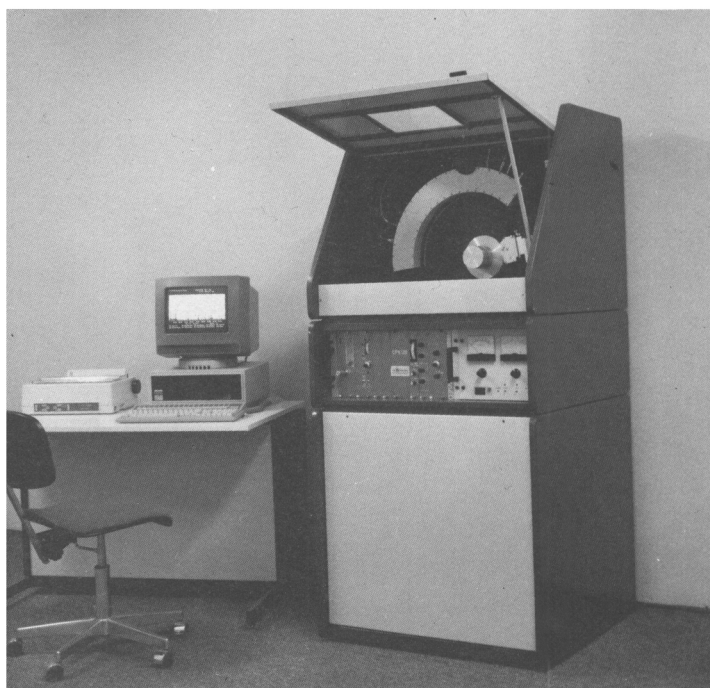
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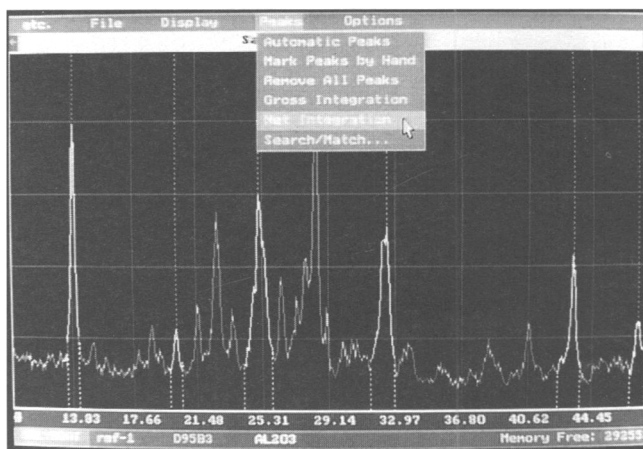
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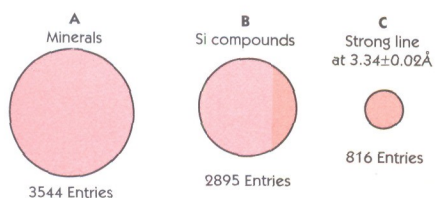
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PD-16

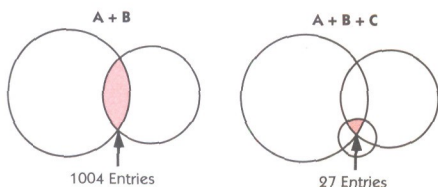
PC-PDF

The Powder Diffraction File on CD-ROM

Search on key fields within the data base.



Search on combinations of fields.



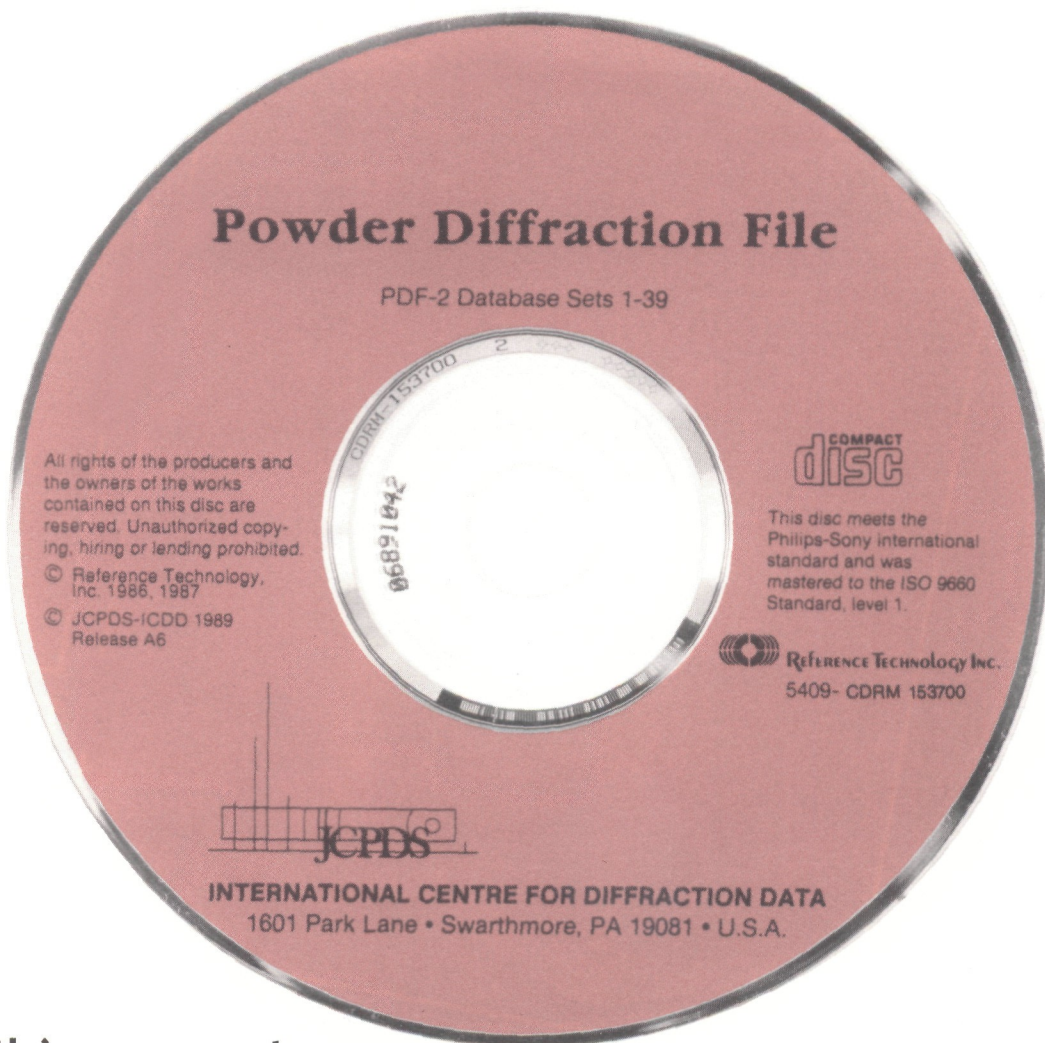
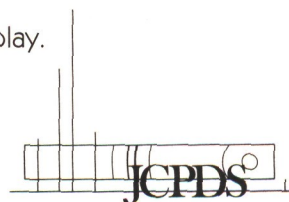
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Editorial

The SUNY/Albany X-ray Clinic

Following the retirement of its Director, Dr. Henry Chessin, the well-known SUNY/Albany X-ray Clinic will no longer be given. This school has been a training experience for more than a thousand X-ray analysts during its 27 years of activity, and it will be missed. It has served the needs of industry in providing training in a laboratory setting for new and experienced individuals working in the XRD and XRF laboratories. Henry Chessin is to be applauded for the success of this program.

The International Centre for Diffraction Data has long recognized the value of the SUNY/Albany Clinic and has participated for many years in its programs. Because of the importance of maintaining this type of instruction for the field of X-ray analysis, the ICDD has agreed to sponsor the continuation of the Clinic beginning in 1990. For 1990, the XRD sections only will be organized. The format of the instructional material will closely follow the two week program presented at the SUNY/Clinic. The first week will be devoted to basic theory and practice and the second week to analysis and problem solving. Many of the same instructors will participate, and Henry Chessin has agreed to act as a consultant for the first year to help in the planning and organization.

The Clinic in 1990 will be held at the Pennsylvania State University in State College, Pennsylvania. The principal organizers will be Dr. Earle Ryba, Department of Materials Science, Pennsylvania State University and Dr. Ron Jenkins,

ICDD, Swarthmore, Pennsylvania. Announcements on registration and content will be found elsewhere in this issue. Planning is well under way at the time of this editorial is being written, and it is very heartening to note the determination of the organizing committee to make this new program a success.

The Education Subcommittee of the ICDD will consider suggestions for the 1991 Clinic including a permanent site, the program content, selection of instructors, and the possibility of continuing the XRF courses portion of the course. This latter question concerning the continuance of XRF courses under ICDD sponsorship comes from the change in charter of ICDD which now includes other diffraction information. There are only a small number of XRF researchers among the ICDD members, so considerable outside help will be necessary for the ICDD to continue this part of the course. Suggestions for the 1991 Clinic may be sent to any member of the organizing staff or to Ron Anderson, IBM Corporation, Hopewell Junction, New York, the Chairman of the Education Subcommittee.

Every effort will be made to carry on the new ICDD Clinic in tradition of the SUNY/Albany Clinic. Its success will be a tribute to its previous organizer, Henry Chessin.

Deane K. Smith
Editor-in-Chief